

Single-Channel: 6N138M, 6N139M Dual-Channel: HCPL2730M, HCPL2731M (Preliminary) Low Input Current High Gain Split Darlington Optocouplers

Features

- Low current – 0.5mA
- Superior CTR-2000%
- Superior CMR-10kV/μs
- CTR guaranteed 0–70°C
- U.L. recognized (File # E90700, Vol. 2)
- VDE recognition (pending)
 - Ordering option V, e.g., 6N138VM
- Dual Channel – HCPL2730M, HCPL2731M (coming soon)

Applications

- Digital logic ground isolation
- Telephone ring detector
- EIA-RS-232C line receiver
- High common mode noise line receiver
- μP bus isolation
- Current loop receiver

Description

The 6N138M/9M and HCPL2730M/31M optocouplers consist of an AlGaAs LED optically coupled to a high gain split darlington photodetector.

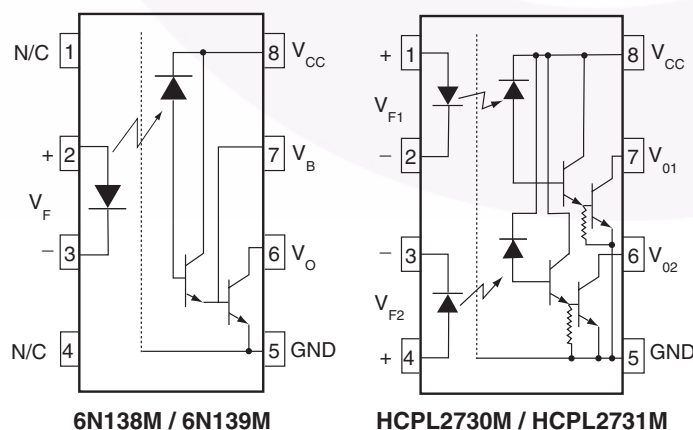
The split darlington configuration separating the input photodiode and the first stage gain from the output transistor permits lower output saturation voltage and higher speed operation than possible with conventional darlington phototransistor optocoupler. In the dual channel devices, HCPL2730M/HCPL2731M, an integrated emitter-base resistor provides superior stability over temperature.

The combination of a very low input current of 0.5mA and a high current transfer ratio of 2000% makes this family particularly useful for input interface to MOS, CMOS, LSTTL and EIA RS232C, while output compatibility is ensured to CMOS as well as high fan-out TTL requirements. An internal noise shield provides exceptional common mode rejection of 10 kV/μs.

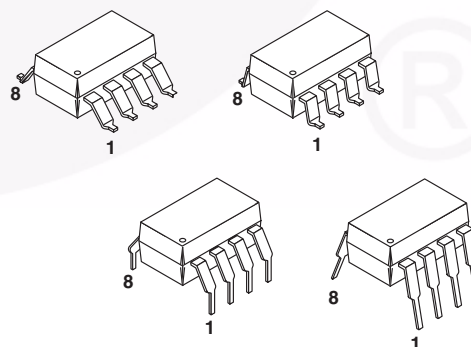
Related Resources

- www.fairchildsemi.com/products/opto/
- www.fairchildsemi.com/pf/HC/HCPL0700.html
- www.fairchildsemi.com/pf/HC/HCPL0730.html
- www.fairchildsemi.com/pf/HC/HCPL0731.html

Schematic



Package Outlines



Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise specified)

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter		Value	Units
T _{STG}	Storage Temperature		-40 to +125	°C
T _{OPR}	Operating Temperature		-40 to +100	°C
T _{SOL}	Lead Solder Temperature (Wave solder only. See recommended reflow profile graph on page 13 for SMD mounting)		260 for 10 sec	°C
EMITTER				
I _F (avg)	DC/Average Forward Input Current	Each Channel	20	mA
I _F (pk)	Peak Forward Input Current (50% duty cycle, 1 ms P.W.)	Each Channel	40	mA
I _F (trans)	Peak Transient Input Current – (≤1μs P.W., 300 pps)		1.0	A
V _R	Reverse Input Voltage	Each Channel	5	V
P _D	Input Power Dissipation ⁽¹⁾	Each Channel	35	mW
DETECTOR				
I _O (avg)	Average Output Current	Each Channel	60	mA
V _{ER}	Emitter-Base Reverse Voltage	6N138M and 6N139M	0.5	V
V _{CC} , V _O	Supply Voltage, Output Voltage	6N138M and HCPL2730M	-0.5 to 7	V
		6N139M and HCPL2731M	-0.5 to 18	
P _O	Output Power Dissipation ⁽¹⁾	Each Channel	100	mW

Note:

1. No derating required for devices operated within the T_{OPR} specification (6N138 and 6N139 only). HCPL2730 and HCPL2731 derating TBD.

Electrical Characteristics

($T_A = 0$ to 70°C unless otherwise specified. Typical value is measured at $T_A = 25^\circ\text{C}$ and $V_{CC} = 5.0\text{V}$.)

Individual Component Characteristics

Symbol	Parameter	Test Conditions	Device	Min.	Typ.	Max.	Unit
EMITTER							
V_F	Input Forward Voltage	$T_A = 25^\circ\text{C}$ Each channel ($I_F = 1.6\text{mA}$)	All		1.30	1.7	V
BV_R	Input Reverse Breakdown Voltage	$T_A = 25^\circ\text{C}$, $I_R = 10\mu\text{A}$	All	5.0	19		V
$\Delta V_F / \Delta T_A$	Temperature Coefficient of Forward Voltage	$I_F = 1.6\text{mA}$	All		-1.94		mV/ $^\circ\text{C}$
DETECTOR							
I_{OH}	Logic HIGH Output Current	$I_F = 0\text{mA}$, $V_O = V_{CC} = 18\text{V}$ Each Channel	6N139M HCPL2731M		0.0036	100	μA
		$I_F = 0\text{mA}$, $V_O = V_{CC} = 7\text{V}$ Each Channel	6N138M HCPL2730M		0.001	250	
I_{CCL}	Logic LOW supply	$I_F = 1.6\text{mA}$, $V_O = \text{Open}$, $V_{CC} = 18\text{V}$ $I_{F1} = I_{F2} = 1.6\text{mA}$, $V_{O1} = V_{O2} = \text{Open}$	6N138M, 6N139M HCPL2731M HCPL2730M		0.4	1.5	mA
		$V_{CC} = 18\text{V}$ $V_{CC} = 7\text{V}$				3	
I_{CCH}	Logic HIGH Supply	$I_F = 0\text{mA}$, $V_O = \text{Open}$, $V_{CC} = 18\text{V}$ $I_{F1} = I_{F2} = 0\text{mA}$, $V_{O1} = V_{O2} = \text{Open}$	6N138M, 6N139M HCPL2731M HCPL2730M		0.0003	10	μA
		$V_{CC} = 18\text{V}$ $V_{CC} = 7\text{V}$				20	

Transfer Characteristics

Symbol	Parameter	Test Conditions	Device	Min.	Typ.	Max.	Unit
COUPLED							
CTR	Current Transfer Ratio ⁽²⁾⁽³⁾	$I_F = 0.5\text{mA}$, $V_O = 0.4\text{V}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N139M HCPL2731M	400	2000		%
		$I_F = 1.6\text{mA}$, $V_O = 0.4\text{V}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N139M HCPL2731M	500	1600		
		$I_F = 1.6\text{mA}$, $V_O = 0.4\text{V}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N138M HCPL2730M	300	1600		
V_{OL}	Logic LOW Output Voltage ⁽³⁾	$I_F = 0.5\text{mA}$, $I_O = 2\text{mA}$, $V_{CC} = 4.5\text{V}$ $I_F = 1.6\text{mA}$, $I_O = 8\text{mA}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N139M 6N139M HCPL2731M		0.05 0.093	0.4	V
		$I_F = 5\text{mA}$, $I_O = 15\text{mA}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N139M HCPL2731M		0.13	0.4	
		$I_F = 12\text{mA}$, $I_O = 24\text{mA}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N139M HCPL2731M		0.18	0.4	
		$I_F = 1.6\text{mA}$, $I_O = 4.8\text{mA}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N138M HCPL2730M		0.06	0.4	

Electrical Characteristics (Continued)

($T_A = 0$ to 70°C unless otherwise specified. Typical value is measured at $T_A = 25^\circ\text{C}$ and $V_{CC} = 5.0\text{V}$.)

Switching Characteristics ($V_{CC} = 5\text{V}$)

Symbol	Parameter	Test Conditions	Device	Min.	Typ.	Max.	Unit
t_{PHL}	Propagation Delay Time to Logic LOW ⁽³⁾ (Fig. 12)	$R_L = 4.7\text{k}\Omega$, $I_F = 0.5\text{mA}$ $T_A = 25^\circ\text{C}$	6N139M		2.5	30	μs
		$R_L = 4.7\text{k}\Omega$, $I_F = 0.5\text{mA}$ Each Channel $T_A = 25^\circ\text{C}$	HCPL2731M			120	
		$R_L = 270\Omega$, $I_F = 12\text{mA}$ $T_A = 25^\circ\text{C}$	6N139M		0.24	2	
		$R_L = 270\Omega$, $I_F = 12\text{mA}$, Each Channel $T_A = 25^\circ\text{C}$	HCPL2730M HCPL2731M			3 2	
		$R_L = 2.2\text{k}\Omega$, $I_F = 1.6\text{mA}$ $T_A = 25^\circ\text{C}$	6N138M		1	15 10	
		$R_L = 2.2\text{k}\Omega$, $I_F = 1.6\text{mA}$, Each Channel $T_A = 25^\circ\text{C}$	HCPL2731M HCPL2730M			25 20	
t_{PLH}	Propagation Delay Time to Logic HIGH ⁽³⁾ (Fig. 12)	$R_L = 4.7\text{k}\Omega$, $I_F = 0.5\text{mA}$ Each Channel	6N139M HCPL2731M			90	μs
		$R_L = 4.7\text{k}\Omega$, $I_F = 0.5\text{mA}$, $T_A = 25^\circ\text{C}$ Each Channel	6N139M HCPL2731M		13.6	60	
		$R_L = 270\Omega$, $I_F = 12\text{mA}$ $T_A = 25^\circ\text{C}$	6N139M		1.3	10 7	
		$R_L = 270\Omega$, $I_F = 12\text{mA}$, Each Channel $T_A = 25^\circ\text{C}$	HCPL2730M HCPL2731M			15 10	
		$R_L = 2.2\text{k}\Omega$, $I_F = 1.6\text{mA}$ Each Channel	6N138M HCPL2730M HCPL2731M			50	
		$R_L = 2.2\text{k}\Omega$, $I_F = 1.6\text{mA}$, $T_A = 25^\circ\text{C}$ Each Channel	6N138M HCPL2730M HCPL2731M		7.3	35	
ICM_{HI}	Common Mode Transient Immunity at Logic HIGH ⁽⁴⁾ (Fig. 13)	$I_F = 0\text{mA}$, $ V_{CM} = 10\text{V}_{P-P}$, $T_A = 25^\circ\text{C}$, $R_L = 2.2\text{k}\Omega$ Each Channel	6N138M 6N139M HCPL2730M HCPL2731M	1,000	10,000		$\text{V}/\mu\text{s}$
ICM_{LI}	Common Mode Transient Immunity at Logic LOW ⁽⁴⁾ (Fig. 13)	$(I_F = 1.6\text{mA}, V_{CM} = 10\text{V}_{P-P}, R_L = 2.2\text{k}\Omega)$ $T_A = 25^\circ\text{C}$ Each Channel	6N138M 6N139M HCPL2730M HCPL2731M	1,000	10,000		$\text{V}/\mu\text{s}$

Electrical Characteristics (Continued)(T_A = 0 to 70°C unless otherwise specified. Typical value is measured at T_A = 25°C and V_{CC} = 5.0V.)**Isolation Characteristics**

Symbol	Characteristics	Test Conditions	Min.	Typ.	Max.	Unit
V _{ISO}	Withstand Insulation Test Voltage ⁽⁵⁾	RH ≤ 50%, T _A = 25°C, I _{I-O} ≤ 10μA, 50Hz, t = 1 min.	5000			V _{RMS}
R _{I-O}	Resistance (Input to Output) ⁽⁵⁾	V _{I-O} = 500VDC		10 ¹¹		Ω
C _{I-O}	Capacitance (Input to Output) ⁽⁵⁾⁽⁶⁾	f = 1MHz, V _{I-O} = 500V		1		pF
I _{I-I}	Input-Input Insulation Leakage Current ⁽⁷⁾	RH ≤ 45%, V _{I-I} = 500VDC, t = 5s, HCPL2730M/2731M only		0.005		μA
R _{I-I}	Input-Input Resistance ⁽⁷⁾	V _{I-I} = 500VDC, HCPL2730M/2731M only		10 ¹¹		Ω
C _{I-I}	Input-Input Capacitance ⁽⁷⁾	f = 1MHz, HCPL2730M/2731M only		0.03		pF

Notes:

- Current Transfer Ratio is defined as a ratio of output collector current, I_O, to the forward LED input current, I_F, times 100%.
- Pin 7 open. (6N138M and 6N139M only)
- Common mode transient immunity in logic HIGH level is the maximum tolerable (positive) dV_{cm}/dt on the leading edge of the common mode pulse signal V_{CM}, to assure that the output will remain in a logic HIGH state (i.e., V_O > 2.0V). Common mode transient immunity in logic LOW level is the maximum tolerable (negative) dV_{cm}/dt on the trailing edge of the common mode pulse signal, V_{CM}, to assure that the output will remain in a logic LOW state (i.e., V_O < 0.8V).
- Device is considered a two terminal device: Pins 1, 2, 3 and 4 are shorted together and Pins 5, 6, 7 and 8 are shorted together.
- For dual channel devices, C_{I-O} is measured by shorting pins 1 and 2 or pins 3 and 4 together and pins 5 through 8 shorted together.
- Measured between pins 1 and 2 shorted together, and pins 3 and 4 shorted together.

Electrical Characteristics (Continued) $T_A = 25^\circ\text{C}$ unless otherwise specified)

Current Limiting Resistor Calculations

$$R_1 \text{ (Non-Invert)} = \frac{V_{DD1} - V_{DF} - V_{OL1}}{I_F}$$

$$R_1 \text{ (Invert)} = \frac{V_{DD1} - V_{OH1} - V_{DF}}{I_F}$$

$$R_2 = \frac{V_{DD2} - V_{OLX} (@ I_L - I_2)}{I_L}$$

Where:

V_{DD1} = Input Supply Voltage

V_{DD2} = Output Supply Voltage

V_{DF} = Diode Forward Voltage

V_{OL1} = Logic "0" Voltage of Driver

V_{OH1} = Logic "1" Voltage of Driver

I_F = Diode Forward Current

V_{OLX} = Saturation Voltage of Output Transistor

I_L = Load Current Through Resistor R_2

I_2 = Input Current of Output Gate

INPUT		R1 (V)	OUTPUT						
			CMOS @ 5V	CMOS @ 10V	74XX	74LXX	74SXX	74LSXX	74HXX
			R2 (V)	R2 (V)	R2 (V)	R2 (V)	R2 (V)	R2 (V)	R2 (V)
CMOS @ 5V	NON-INV.	2000	1000	2200	750	1000	1000	1000	560
	INV.	510							
CMOS @ 10V	NON-INV.	5100							
	INV.	4700							
74XX	NON-INV.	2200							
	INV.	180							
74LXX	NON-INV.	1800							
	INV.	100							
74SXX	NON-INV.	2000							
	INV.	360							
74LSXX	NON-INV.	2000							
	INV.	180							
74HXX	NON-INV.	2000							
	INV.	180							

Fig. 1 Resistor Values for Logic Interface

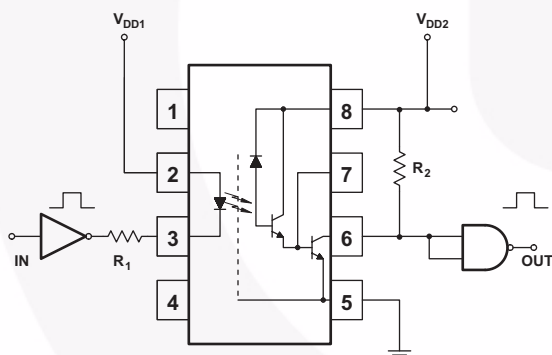


Fig. 2 Non-Inverting Logic Interface

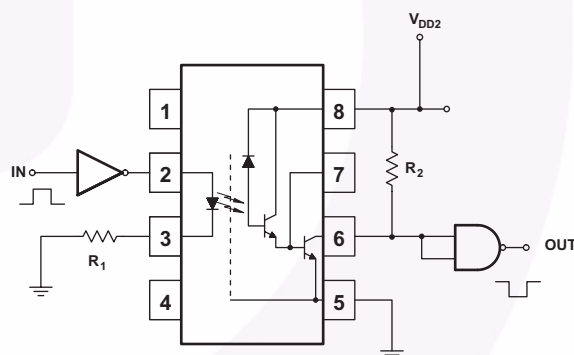


Fig. 3 Inverting Logic Interface

Typical Performance Curves

Fig. 4 LED Forward Current vs. Forward Voltage

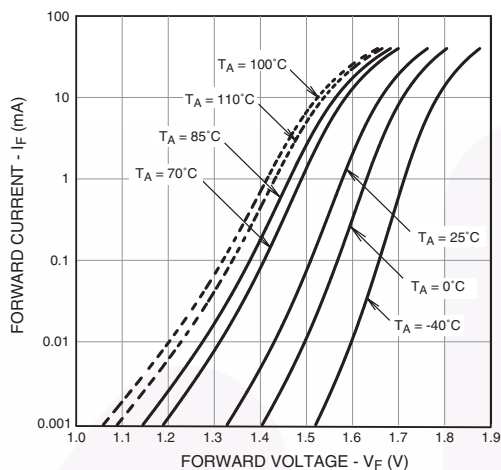


Fig. 5 LED Forward Voltage vs. Temperature

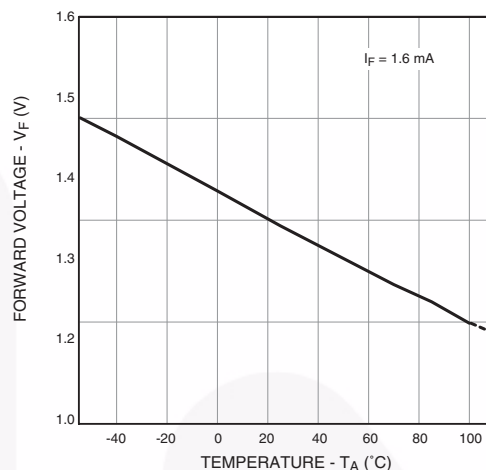


Fig. 6 Current Transfer Ratio vs. Forward Current (6N138M / 6N139M Only)

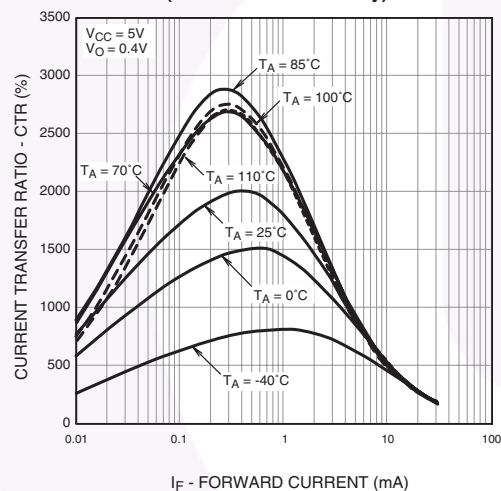


Fig. 7 Normalized Current Transfer Ratio vs. Ambient Temperature (6N138M / 6N139M Only)

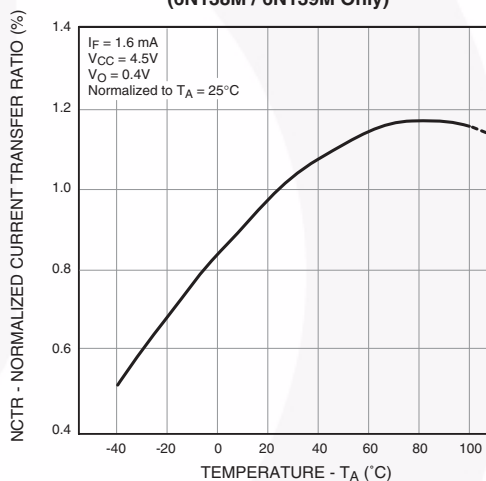


Fig. 8 Current Transfer Ratio vs. Base-Emitter Resistance (6N138M / 6N139M Only)

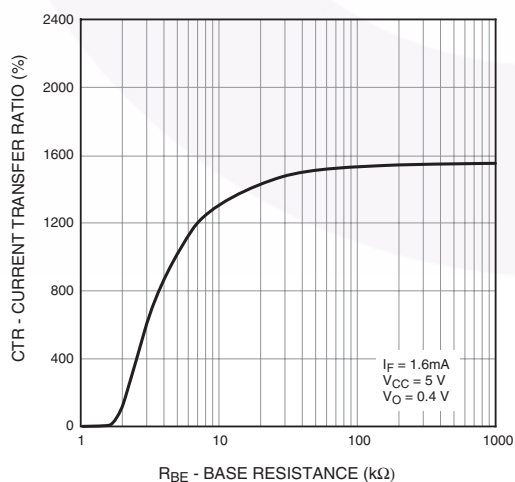
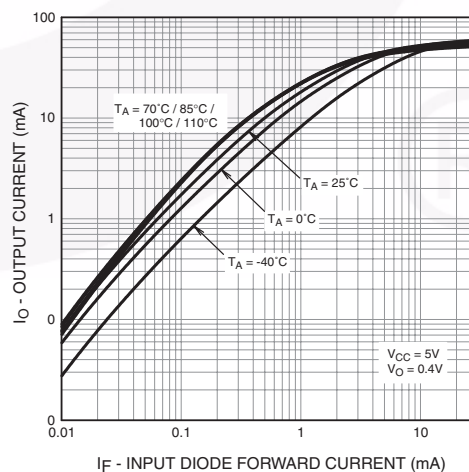


Fig. 9 Output Current vs. Input Diode Forward Current (6N138M / 6N139M Only)



Typical Performance Curves (Continued)

Fig. 10 Output Current vs Output Voltage
(6N138M / 6N139M Only)

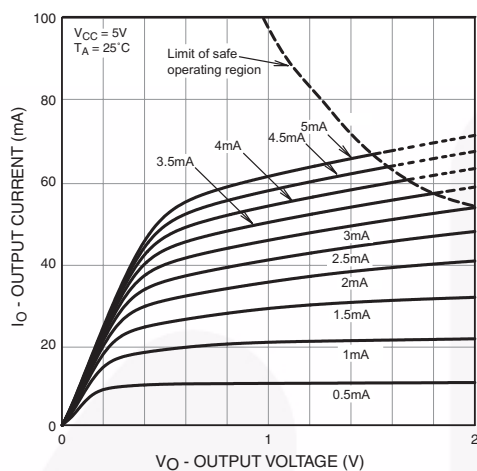


Fig. 11 Logic Low Supply Current vs. Input Diode Forward Current
(6N138M / 6N139M Only)

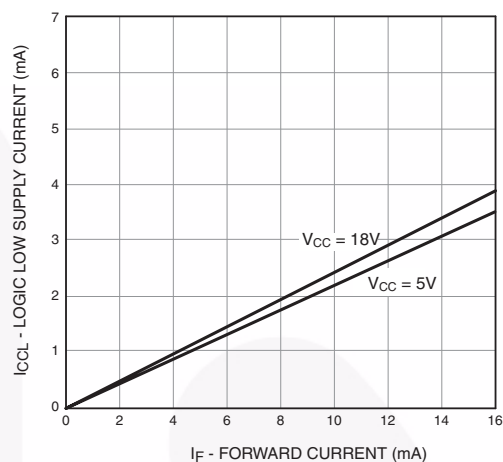
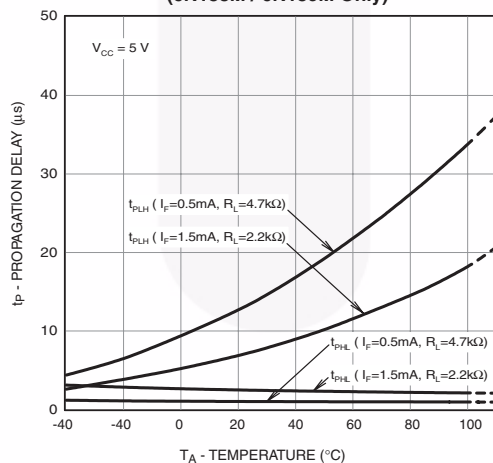
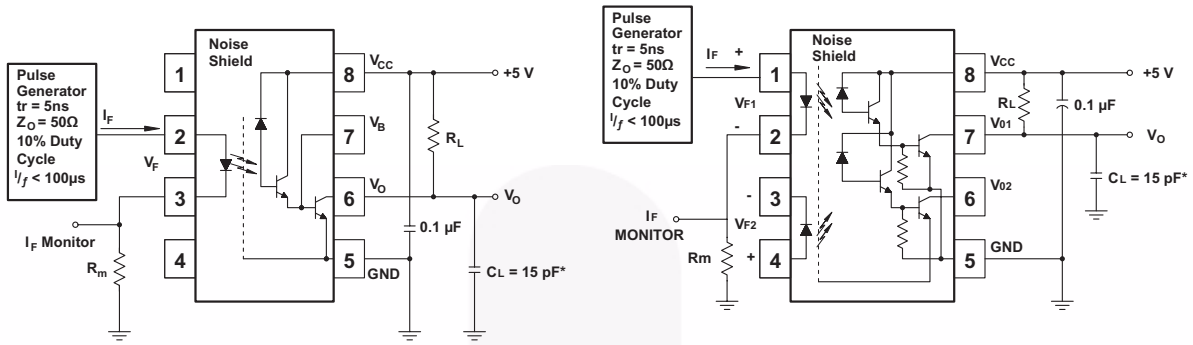


Fig. 12 Propagation Delay vs. Temperature
(6N138M / 6N139M Only)



Test Circuits



Test Circuit for 6N138M, 6N139M

Test Circuit for HCPL2730M and HCPL2731M

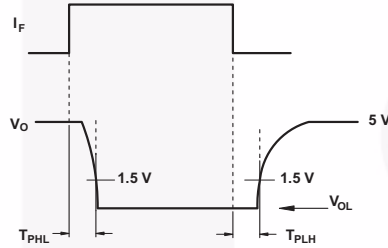
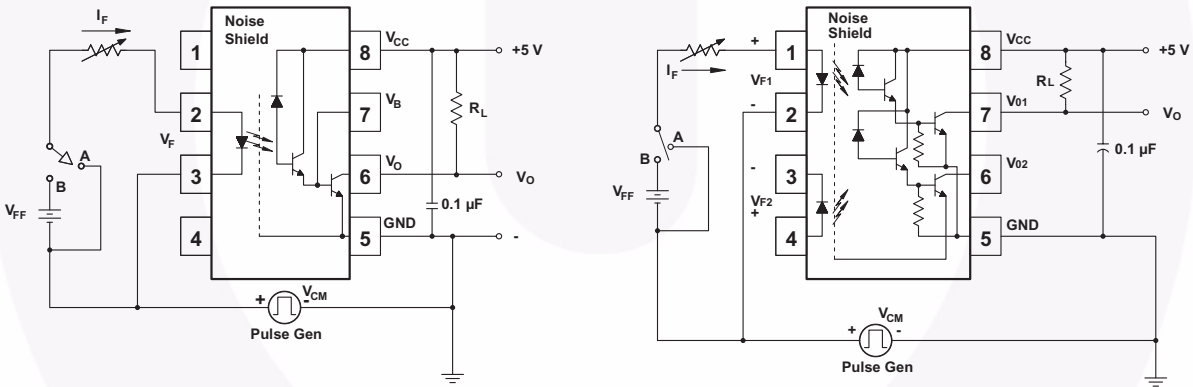


Fig. 13 Switching Time Test Circuit



Test Circuit for 6N138M and 6N139M

Test Circuit for HCPL2730M and HCPL2731M

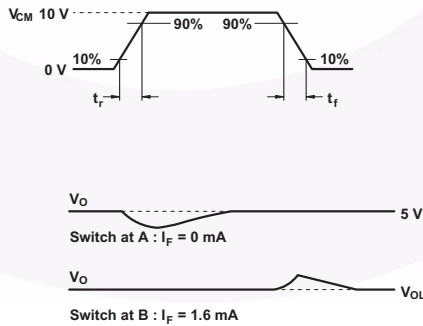
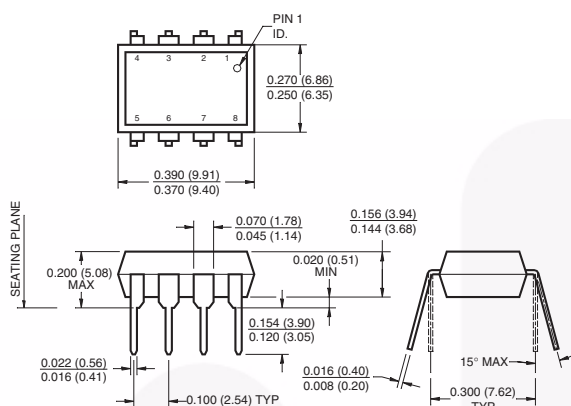


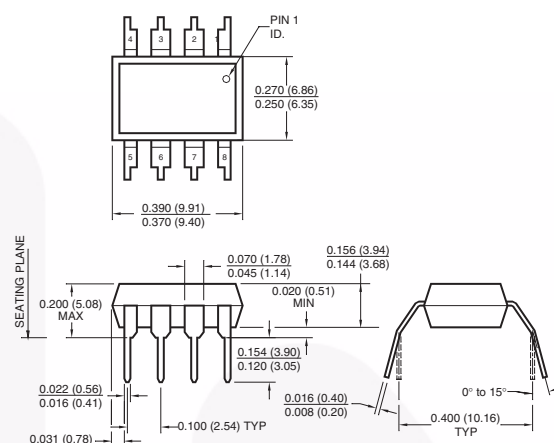
Fig. 14 Common Mode Immunity Test Circuit

Package Dimensions

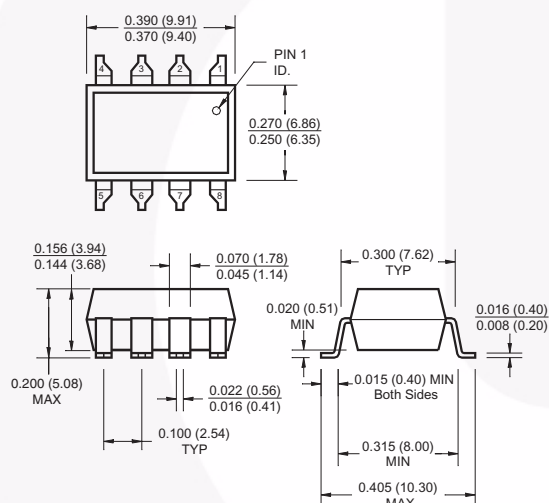
Through Hole



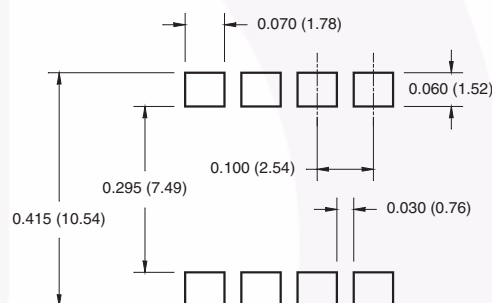
0.4" Lead Spacing (Option TV) (Pending)



Surface Mount – 0.3" Lead Spacing (Option S)



8-Pin Surface Mount DIP – Land Pattern (Option S)



Note:

All dimensions are in inches (millimeters)

Package drawings are provided as a service to customers considering Fairchild components. Drawings may change in any manner without notice. Please note the revision and/or date on the drawing and contact a Fairchild Semiconductor representative to verify or obtain the most recent revision. Package specifications do not expand the terms of Fairchild's worldwide terms and conditions, specifically the warranty therein, which covers Fairchild products.

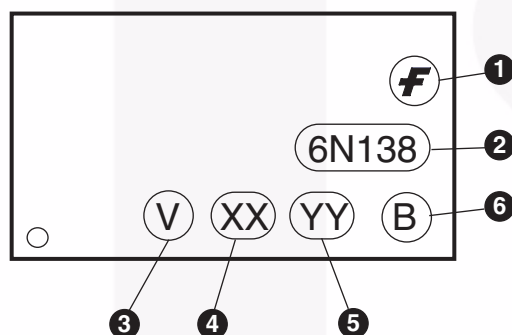
Always visit Fairchild Semiconductor's online packaging area for the most recent package drawings:

<http://www.fairchildsemi.com/packaging/>

Ordering Information

Option	Example Part Number	Description
No Suffix	6N138M	Standard Through Hole Device, 50 pcs per tube
S	6N138SM	Surface Mount Lead Bend
SD	6N138SDM	Surface Mount; Tape and reel
V	6N138VM	IEC60747-5-2 approval pending (VDE)
TV	6N138TVM	IEC60747-5-2 approval pending (VDE); 0.4" lead spacing
SV	6N138SVM	IEC60747-5-2 approval pending (VDE); surface mount
SDV	6N138SDVM	IEC60747-5-2 approval pending (VDE); surface mount; tape and reel

Marking Information



Definitions	
1	Fairchild logo
2	Device number
3	VDE mark (Note: Only appears on parts ordered with VDE option – See order entry table) (pending approval)
4	Two digit year code, e.g., '07'
5	Two digit work week ranging from '01' to '53'
6	Assembly package code

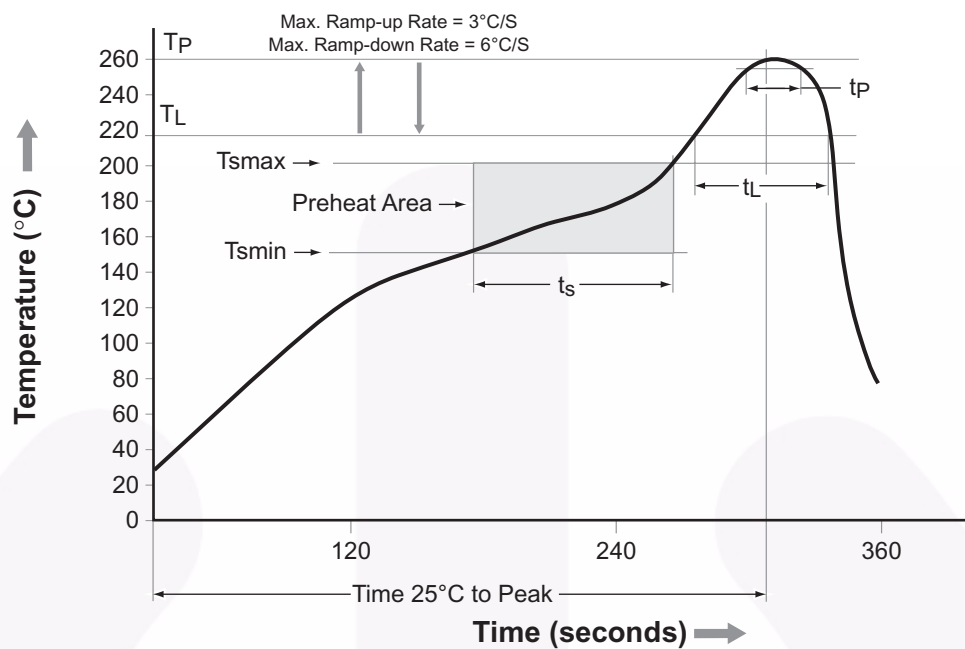
Note:

'HCPL' devices are marked only with the numerical characters (for example, HCPL2730 is marked as '2730').

The 'M' suffix on the part number is an order identifier only. It is used to identify orders for the white package version. The 'M' does not appear on the device's top mark.

Symbol	Description	Dimension in mm
W	Tape Width	16.0 ± 0.3
t	Tape Thickness	0.30 ± 0.05
P ₀	Sprocket Hole Pitch	4.0 ± 0.1
D ₀	Sprocket Hole Diameter	1.55 ± 0.05
E	Sprocket Hole Location	1.75 ± 0.10
F	Pocket Location	7.5 ± 0.1
P ₂		2.0 ± 0.1
P	Pocket Pitch	12.0 ± 0.1
A ₀	Pocket Dimensions	10.30 ±0.20
B ₀		10.30 ±0.20
K ₀		4.90 ±0.20
W ₁	Cover Tape Width	13.2 ± 0.2
d	Cover Tape Thickness	0.1 max
	Max. Component Rotation or Tilt	10°
R	Min. Bending Radius	30

Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T _{smin})	150°C
Temperature Max. (T _{smax})	200°C
Time (t _s) from (T _{smin} to T _{smax})	60–120 seconds
Ramp-up Rate (t _L to t _p)	3°C/second max.
Liquidous Temperature (T _L)	217°C
Time (t _L) Maintained Above (T _L)	60–150 seconds
Peak Body Package Temperature	260°C +0°C / –5°C
Time (t _p) within 5°C of 260°C	30 seconds
Ramp-down Rate (T _p to T _L)	6°C/second max.
Time 25°C to Peak Temperature	8 minutes max.



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EZSWITCH™*
™
Fairchild®
Fairchild Semiconductor®
FACT Quiet Series™
FACT®
FAST®
FastvCore™
FETBench™

FlashWriter®*
FPS™
F-PFS™
FRFET®
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Green FPS™
Green FPS™ e-Series™
Gmax™
GTO™
IntelliMAX™
ISOPANAR™
MegaBuck™
MICROCOUPLER™
MicroFET™
MicroPak™
MillerDrive™
MotionMax™
Motion-SPM™
OPTOLOGIC®
OPTOPLANAR®
™
PDP SPM™

Power-SPM™
PowerTrench®
PowerXS™
Programmable Active Droop™
QFET®
QS™
Quiet Series™
RapidConfigure™
™
Saving our world, 1mW/W/kW at a time™
SignalWise™
SmartMax™
SMART START™
SPM®
STEALTH™
SuperFET™
SuperSOT™-3
SuperSOT™-6
SuperSOT™-8
SupreMOS™
SyncFET™
Sync-Lock™

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The Power Franchise®
the **power**™
franchise
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Definition of Terms

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